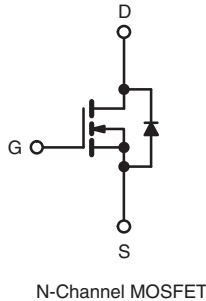
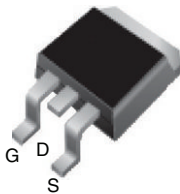


# N-Channel 600-V (D-S) Super Junction MOSFET

## PRODUCT SUMMARY

$V_{DS}$ at $T_J$ max. (V)	600	
$R_{DS(on)}$ max. at 25 °C ( $\Omega$ )	$V_{GS} = 10\text{ V}$	0.190
$Q_g$ max. (nC)	98	
$Q_{gs}$ (nC)	17	
$Q_{gd}$ (nC)	25	
Configuration	Single	

**D<sup>2</sup>PAK (TO-263)**


## FEATURES

- Generation one
- High  $E_{AR}$  capability
- Lower figure-of-merit  $R_{on} \times Q_g$
- 100 % avalanche tested
- Ultra low  $R_{on}$
- $dV/dt$  ruggedness
- Ultra low gate charge ( $Q_g$ )

## APPLICATIONS

- PFC power supply stages
- Hard switching topologies
- Solar inverters
- UPS
- Motor control
- Lighting
- Server telecom



**RoHS**  
 COMPLIANT  
 HALOGEN  
**FREE**  
 Available


## ABSOLUTE MAXIMUM RATINGS ( $T_C = 25\text{ °C}$ , unless otherwise noted)

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V <sub>DS</sub>	600	V
Gate-Source Voltage			V <sub>GS</sub>	± 30	
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	20	A
		T <sub>C</sub> = 100 °C		13	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	65	
Linear Derating Factor		D <sup>2</sup> PAK (TO-263)		2	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	690	mJ
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	25	
Maximum Power Dissipation		D <sup>2</sup> PAK (TO-263)	P <sub>D</sub>	250	W
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt	37	V/ns
Reverse Diode dV/dt <sup>d</sup>				5.3	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	

### Notes

- Repetitive rating; pulse width limited by maximum junction temperature.
- $V_{DD} = 50\text{ V}$ , starting  $T_J = 25\text{ °C}$ ,  $L = 28.2\text{ mH}$ ,  $R_g = 25\text{ }\Omega$ ,  $I_{AS} = 7\text{ A}$ .
- 1.6 mm from case.
- $I_{SD} \leq I_D$ ,  $dI/dt = 100\text{ A}/\mu\text{s}$ , starting  $T_J = 25\text{ °C}$ .

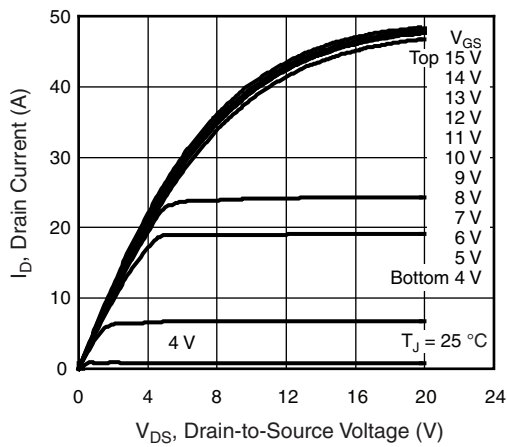
THERMAL RESISTANCE RATINGS					
PARAMETER		SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	D <sup>2</sup> PAK (TO-263)	R <sub>thJA</sub>	-	62	°C/W
Maximum Junction-to-Case (Drain)	D <sup>2</sup> PAK (TO-263)	R <sub>thJC</sub>	-	0.5	

SPECIFICATIONS (T <sub>J</sub> = 25 °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA		600	-	-	V
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.70	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
		V <sub>GS</sub> = ± 30 V		-	-	± 1	μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V		-	-	1	μA
		V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C		-	-	100	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 11 A	-	0.190	-	Ω
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 13 A		-	9.4	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1.0 MHz		-	2810	-	pF
Output Capacitance	C <sub>oss</sub>			-	1480	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	33	-	
Effective Output Capacitance (Time Related)	C <sub>oss eff. (TR)</sub> <sup>a</sup>	V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 0 V to 480 V	-	155	-	nC
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 22 A, V <sub>DS</sub> = 480 V	-	75	110	
Gate-Source Charge	Q <sub>gs</sub>			-	17	-	
Gate-Drain Charge	Q <sub>gd</sub>			-	25	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 380 V, I <sub>D</sub> = 22 A, R <sub>g</sub> = 9.1 Ω, V <sub>GS</sub> = 10 V		-	24	50	ns
Rise Time	t <sub>r</sub>			-	68	100	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	77	115	
Fall Time	t <sub>f</sub>			-	59	90	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	0.65	-	Ω
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode 		-	-	22	A
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	88	
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 22 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> , di/dt = 100 A/μs, V <sub>R</sub> = 25 V		-	462	690	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	8.3	16	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	30	60	A

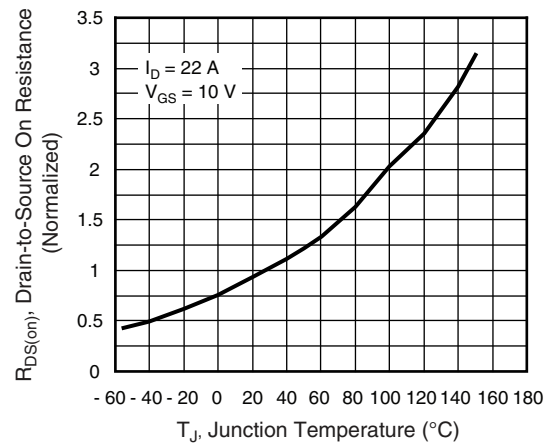
#### Note

a. C<sub>oss eff. (TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 % to 80 % V<sub>DS</sub>.

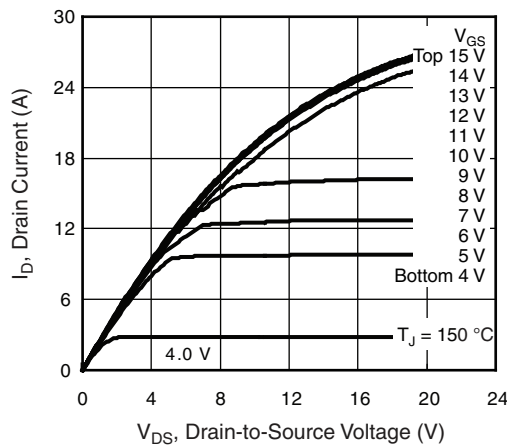
# **TYPICAL CHARACTERISTICS** (25 °C, unless otherwise noted)



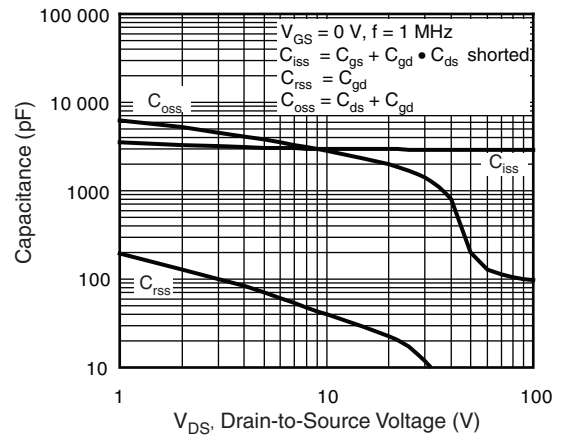
**Fig. 1 - Typical Output Characteristics,  $T_J = 25^\circ\text{C}$**



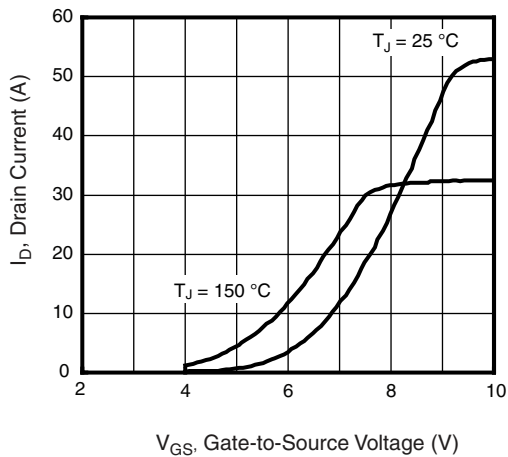
**Fig. 4 - Normalized On-Resistance vs. Temperature**



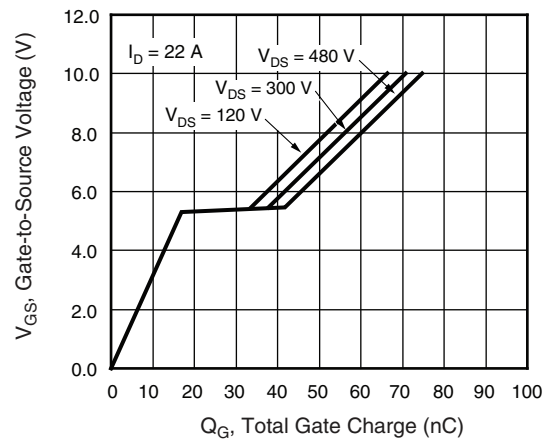
**Fig. 2 - Typical Output Characteristics,  $T_J = 150^\circ\text{C}$**



**Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage**



**Fig. 3 - Typical Transfer Characteristics**



**Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage**

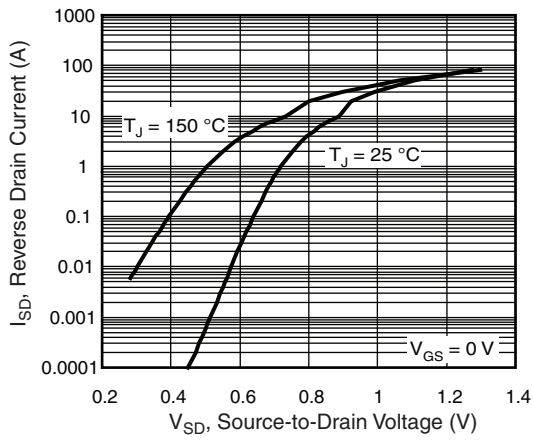


Fig. 7 - Typical Source-Drain Diode Forward Voltage

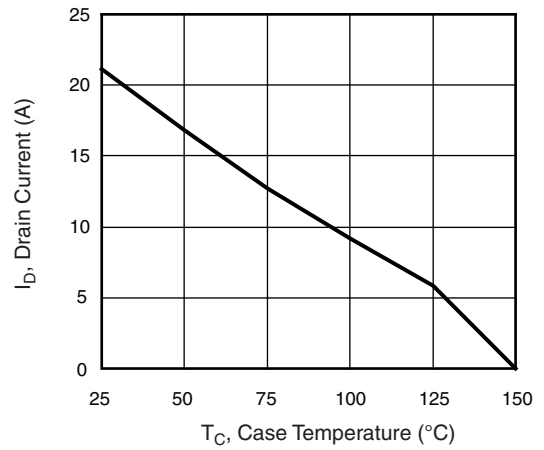


Fig. 9 - Maximum Drain Current vs. Case Temperature

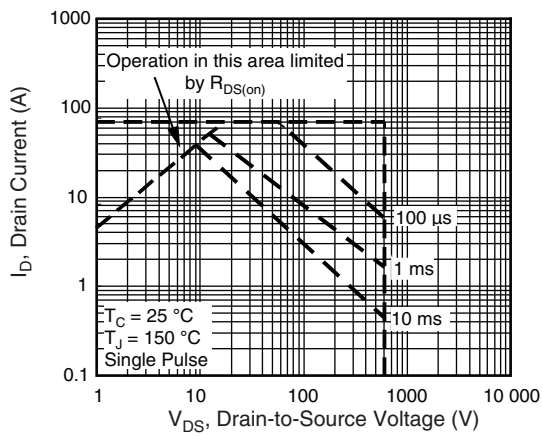


Fig. 8 - Maximum Safe Operating Area

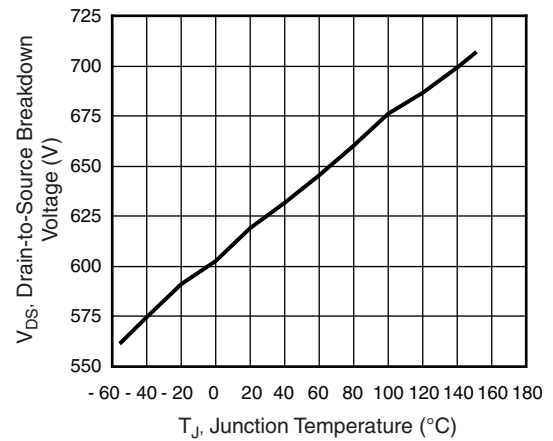


Fig. 10 - Drain-to-Source Breakdown Voltage

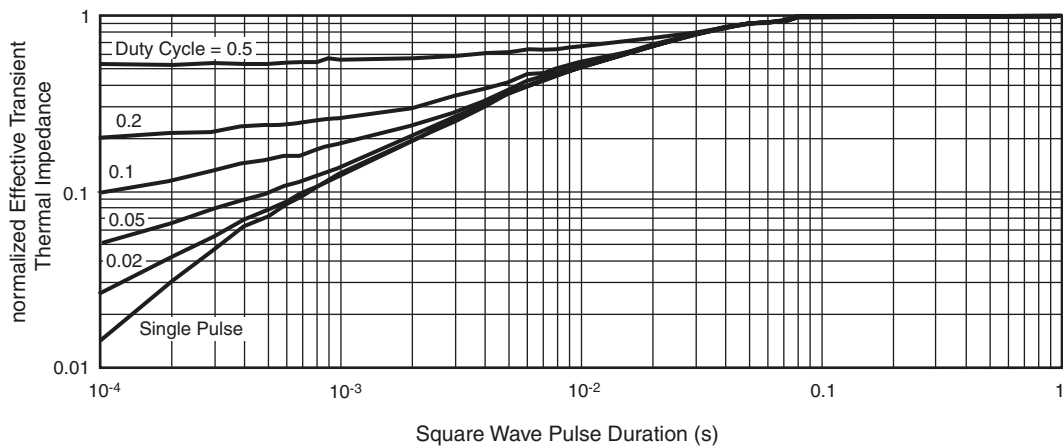
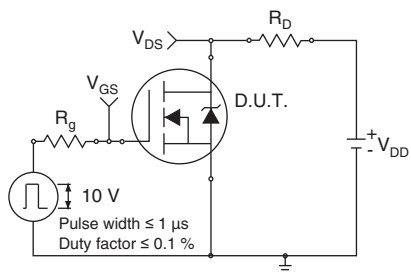
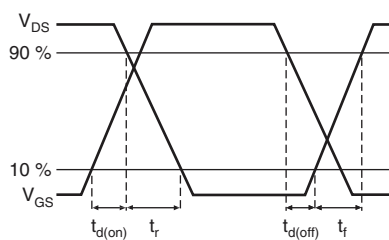


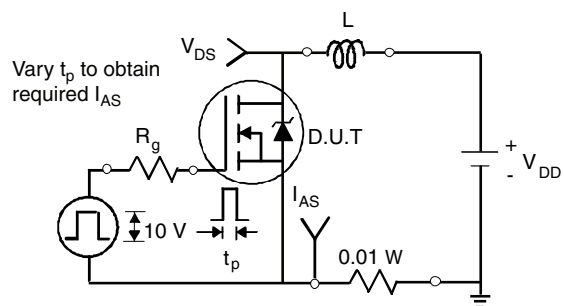
Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



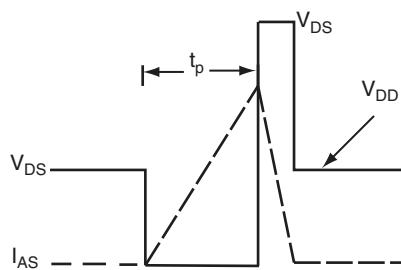
**Fig. 12 - Switching Time Test Circuit**



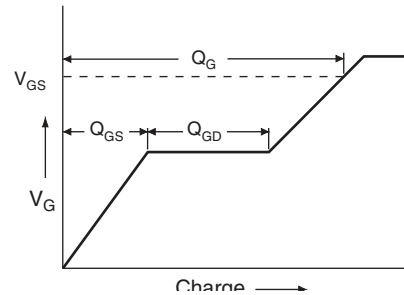
**Fig. 13 - Switching Time Waveforms**



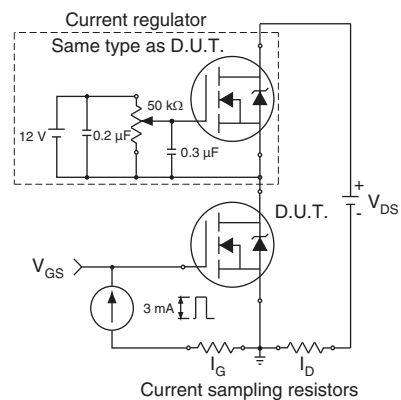
**Fig. 14 - Unclamped Inductive Test Circuit**



**Fig. 15 - Unclamped Inductive Waveforms**

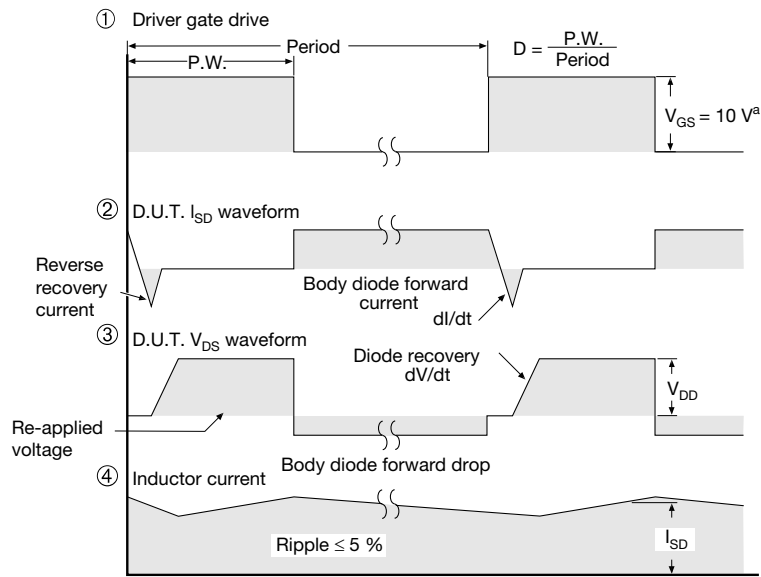
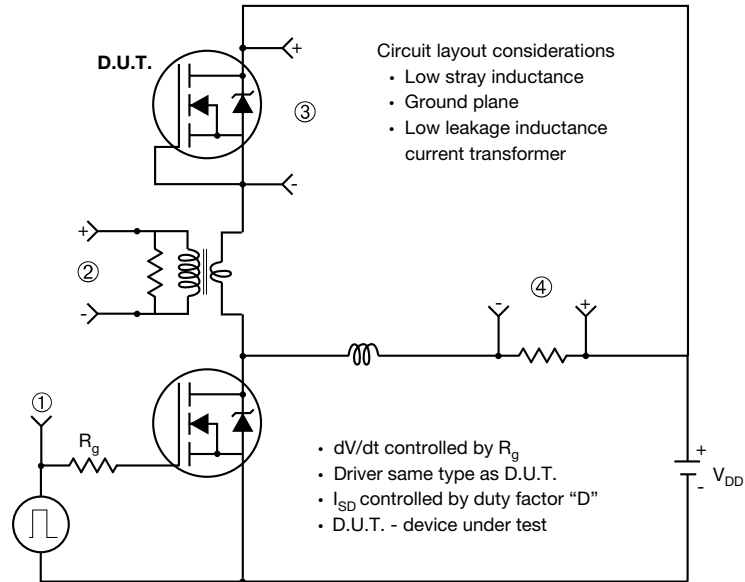


**Fig. 16 - Basic Gate Charge Waveform**



**Fig. 17 - Gate Charge Test Circuit**

### Peak Diode Recovery $dV/dt$ Test Circuit

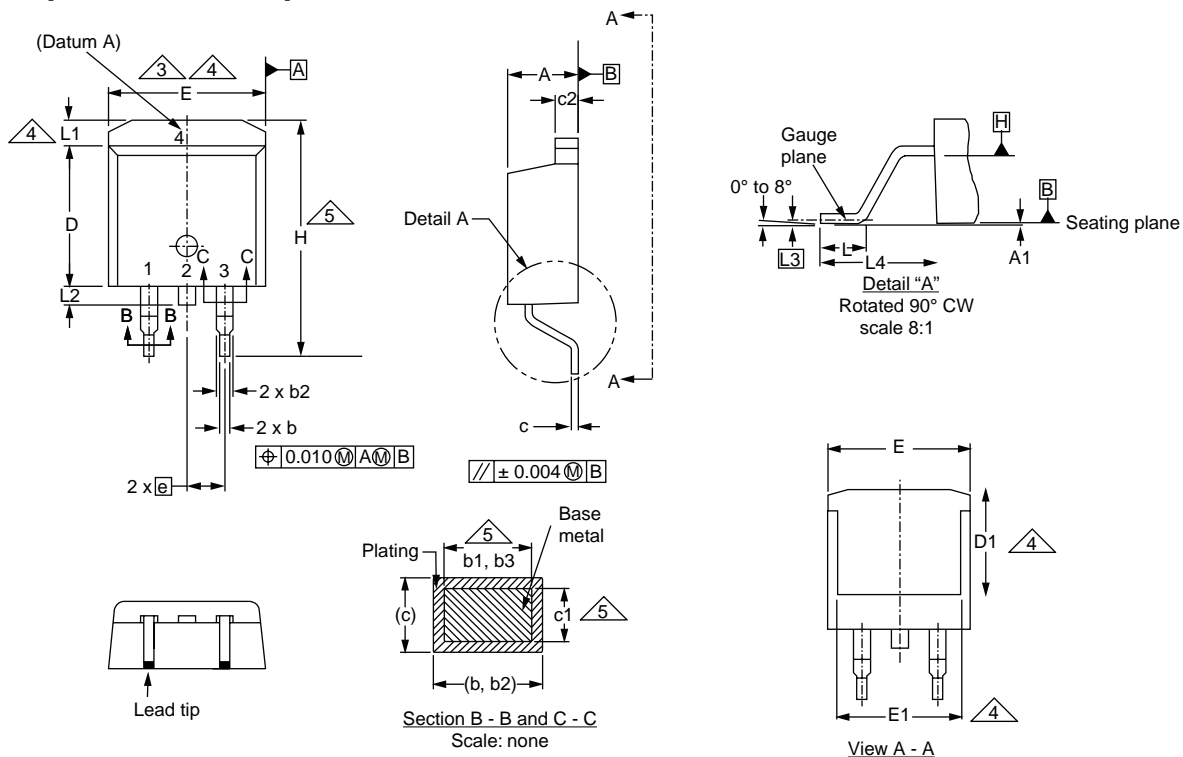


#### Note

a.  $V_{GS} = 5 V$  for logic level devices

**Fig. 18 - For N-Channel**

## TO-263AB (HIGH VOLTAGE)



	MILLIMETERS		INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
A	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
c	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

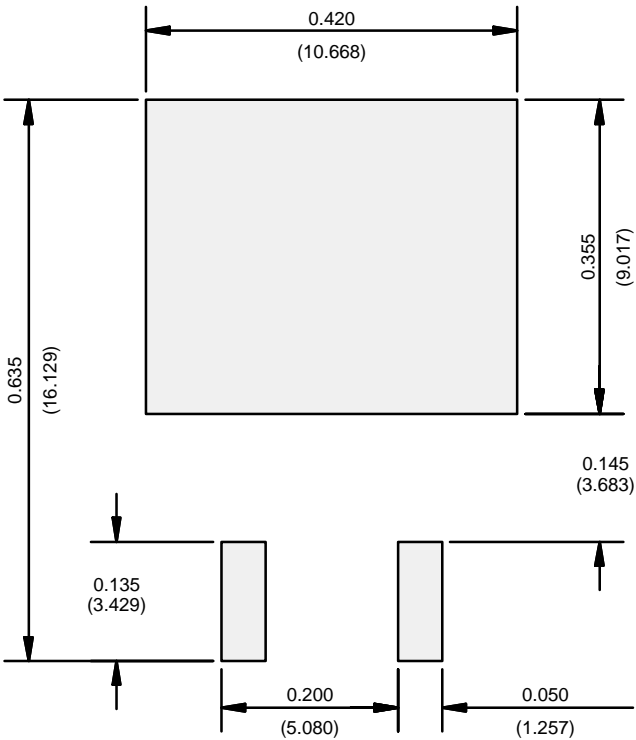
	MILLIMETERS		INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
e	2.54 BSC		0.100 BSC	
H	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010 BSC	
L4	4.78	5.28	0.188	0.208

ECN: S-82110-Rev. A, 15-Sep-08  
DWG: 5970

## Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.
2. Dimensions are shown in millimeters (inches).
3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
5. Dimension b1 and c1 apply to base metal only.
6. Datum A and B to be determined at datum plane H.
7. Outline conforms to JEDEC outline to TO-263AB.

**RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead**



Recommended Minimum Pads  
Dimensions in Inches/(mm)



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